METHOD AND SYSTEM FOR MEASURING A PROPAGATION DELAY AND TRANSMITTANCE OF A DEVICE UNDER TEST (DUT)

ABSTRACT

The invention provides a method and system for measuring a propagation delay of a device under test (DUT) using a first measurement unit and a second measurement unit. A first periodic signal transmitted from the first measurement unit via the DUT is received at the second measurement unit as a first delayed periodic signal. The first delayed periodic signal is then compared with a second periodic signal at the second measurement unit to generate the second comparison phase output. Similarly, the second periodic signal transmitted from the second measurement unit via the DUT is received at the first measurement unit as a second delayed periodic signal. The second delayed periodic signal is then compared with the first periodic signal at the first measurement unit to generate the first comparison phase output. Thereafter, the propagation delay is calculated by combining the first comparison phase output and the second comparison phase output.

FIG. 1